

**Notic of R ferences Cited**

Application/Control No.

09/750,489

Applicant(s)/Patent Under

Reexamination

YAUNG, ALAN T.

Examiner

VAN H NGUYEN

Art Unit

2126

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,563,836 B1	05-2003	Capps et al.	370/412
	B	US-6,546,428 B2	04-2003	Baber et al.	709/232
	C	US-6,529,932 B1	03-2003	Dadiomov et al.	709/101
	D	US-6,449,646 B1	09-2002	Sikora et al.	709/226
	E	US-6,425,017 B1	07-2002	Dievendorff et al.	709/315
	F	US-6,401,136 B1	06-2002	Britton et al.	709/314
	G	US-6,226,689 B1	05-2001	Shah et al.	709/314
	H	US-6,058,389 A	05-2000	Chandra et al.	707/1
	I	US-5,699,523 A	12-1997	Li et al.	709/238
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.